

800 W. 6th Street, Austin, TX 78701

PCN-2014-552

Assembly and Test Site Transfer from StatsChipPac Kuala Lumpur, Malaysia (SCM) to ASE-Chung Li (ASE-CL) Taiwan for the CS35L00-CNZ(R) component

Process/Product Change Notification (Reference Advance PCN-2014-534)

Date: June 2014

Dear Customer:

This is a Final Announcement of the Assembly and Test Site Transfer from StatsChipPac Kuala Lumpur, Malaysia to ASE-Chung Li (ASE-CL) Taiwan for the CS35L00-CNZ(R) component that is currently offered by Cirrus Logic. This Final announcement is a follow on to the Advance PCN notification communicated to all customers in February of this calendar year 2014. The details of this Assembly and Test Site Transfer are outlined on the following pages.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the lifetime buy offering/discontinuance plan.

The described change(s) within this PCN will not be realized or take effect any earlier than **60** days from the date of this notification, unless a customer agreement has been reached on an earlier implementation of the change or successful completion of the defined qualification has been realized.

Please note that the notification period has been reduced from 90 days to 60 days as the SCM site recently informed Cirrus that the closure date has been moved forward from December 31^{st} , 2014 to September 30^{th} , 2014. Cirrus has no control over any changes to the site closure date.

Any negotiated alternative change requirements will be provided via the customer's defined process. Customers with previously negotiated, special requirements will be handled separately. Cirrus Logic would like to take this opportunity to thank our customers for their cooperation and assistance in this respective matter. Any specific or immediate inquiries should be directed to your local Field Sales Representative.

Sincerely,

PCN Coordinator Cirrus Logic Corporate Quality Phone: +1(512) 851-4000

Attachment: 1

Products Affected:

The devices listed on this page are the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

Technical details of this Process / Product Change follow on the next page(s).

PCN Number:			201	2014-552		PCN Date:				June 2014	
Title:	tle: Assembly and Test Site Transfer from StatsChipPac Kuala Lumpur, Malaysia to A					alaysia to ASE-					
	Chung Li (ASE-CL) Taiwan for the CS35L00-CNZ(R) component										
Customer Local Field			ld Sa	les		•	(512)		Dep		
Contact: Represen		ntativ	е		851-4000			Quality			
Proposed 1 st Ship Date:				August 2014	Estimated Sample					May 2014	
				Availability date:							
Change Type: Ass			Ass	embly and Test Site Transfer to an existing Qualified Cirrus Logic							
S			Site	ite Location: Change Type = Major							
Assembly Site				Assembly Process			\boxtimes	Assen	nbly I	Materials	
	Design			Electrical Specif	ication			Mecha	anica	I Specification	
\square	Test Sit	e		Packing/Shipping/Labeli				Test F	Proce	SS	
	Wafer Bump Site		Wafer Bump Material				Wafer	r Bun	np Process		
	Wafer F	ab Site		Wafer Fab Mate	rials			Wafer	r Fab	Process	

PCN Details

Description of Change:

Cirrus Logic's package Assembly and Test Supplier, StatsChipPac, has announced their site in Kuala Lumpur, Malaysia will close by September 30th, 2014.

Cirrus Logic is qualifying and will move these products to the existing qualified subcontractor (ASE-CL) site location in Chung Li Taiwan.

Below you will find an outline of the described changes for these components:

CS35L00-CNZ(R)

 Assembly and Test Site Change: From: StatsChipPac Kuala Lumpur Taiwan Mold Compound: 	, Malaysia	÷	To: ASE-Chung Li (ASE-CL)
 From: Sumitomo EME-G770 DIE Attach: 	\rightarrow		To: Hitachi CEL-9240HF
From: Ablebond 8290	\rightarrow		To: Henkel ABT125
Reason for Change:			

Cirrus Logic's package Assembly and Test Supplier, StatsChipPac, has announced their site in Kuala Lumpur, Malaysia will close by September 30th, 2014.

Cirrus Logic is qualifying and will move these products to the existing qualified subcontractor (ASE-CL) site location in Chung Li Taiwan.

Special Note:					
As a full services supplier and in order to ensure continuit accelerated timeframe has been established for the full tr September 30th, 2014.					
arlier production level material may be available from the qualified subcontractor (ASE-CL) site ocation in Chung Li Taiwan, but shipment(s) from Cirrus Logic are contingent on successful ompletion of the designated site transfer qualification.					
Anticipated impact on Form, Fit, Function, Quality o	r Reliability (positive / negative):				
Anticipated No Adverse Impact to the Quality & Reliability existing Cirrus Logic qualified subcontractor (ASE-Chung considered low risk.					
Product Affected:					
Customer Part Number	Cirrus Logic Part Number				
Device 1:	CS35L00-CNZ(R)				
Changes to product identification resulting from thi	s PCN:				
The Cirrus Logic component symbolization on the external face of the device reflects the designated Assembly Vendor.					
Below you will find a representative example:					
Our part: CS35L00-CNZ(R) Mark format: 300 Mark change: · Assembly Vendor = AA changing From: MA → TO: AC · COO = None (not shown on mark) Line 1: Part Number (4 spaces max.)					
Line 2: Package Mark (4 spaces max.) Line 3: Date Code (4 spaces max.)					
PN 1 Identifier (laser marked) XXXXX AALL YYWWW With the Assembly and Test Site Transfer to ASE-Chung I	_i (ASE-CL) Taiwan, the material will				
receive the appropriate designation for the Assembly Vendor.					

Qualification Data:

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.							
Qualification Schedule:	Start:	March 2014		End:	July 2014		
Qualification Device Const							
	Device 1	7(0)	Device 2				
Part Number(s):	CS35L00-CN	Z(R)					
Wafer Fab Site:	35						
Wafer Technology:	0.18 um						
Die Size:	1.56 mm						
Assembly Site:	ASE-Chung Li (ASE-CL) Taiwan						
Package Type/Code:	10DFNZ VQFN 3x3						
Moisture Level:	MSL (Moisture Sensitivity Level) 2						
Package Pins:	10 NL QFN						
Lead Frame Material:	Cu (Copper)						
Mold Compound	CEL-9240HF						
Supplier:	Hitachi						
Lead Finish:	Matte Sn Plat	e					
Die / Pad	0.308						
Die Attach Material	Henkel ABT12	25					
Wire Diameter:	0.8 mil						
Wire Base Metal:	PCC						

The Qualification Plans are designed using JEDEC and other applicable industry standards. An overall summary of the Qualification results will be submitted upon completion.

CS35L00-CNZ(R) Qualification

CS35L00-CNZ(R) Qualification:	🛛 Plan	Test Results	
Reliability Test			Sample Size
Reliability rest			(PASS/FAIL)

Pre-Conditioning	JEDEC J-STD-020A	MSL2 / 260°C (2 Lots)	462 / 0
BHAST (Biased HAST)	JESD22 A101	130C/85%RH/96 hrs (BHAST) Read Points (96 Hrs) (1 Lot)	77 / 0
Temperature Cycle	JESD22 A104	-65°C to +150°C for 500 cycles (1 Lot)	77 / 0
WBS (Wire Bond Shear)	JESD22 B116	Paragraph 4 (Procedure) (1 Lot)	5 units / lot
WBP (Wire Bond Pull)	MIL-STD-883 Method 2011	Paragraph 3 (Procedure) (1 Lot)	5 units / lot
SD (Solderability)	JESD22 B102	93°C / 8 hr steam age before SD (1 Lot)	15 Units / 0
PD (Physical Dimensions)	JESD22 B100 + B108	Package outline per JESD95 Cpk > 1.50 per JESD95 (1 Lot)	10 / 0
HTSL (High Temperature Storage Life)	JESD22 A103	150°C for 1000 hrs (1 Lot)	45 / 0
Notes: • Qualification test	s "pass" on zero f	ails for each test	

Test Equipment Correlation Plan

Note:

- The Equipment Platform Technology, Hardware and Software remain the same.
- The Visual / Mechanical inspection and Tape and Reel operations are compliant to JEDEC industry standards

The Test Equipment Correlation plan involves the following:

- Running the new site program with an OPEN Socket (No Unit) to ensure "All" tests fail.
- Serializing Control (Known Good) Units and testing the material on both test platforms (Existing and New Location) at all applicable test temperatures utilizing the same load-board and test site(s). A correlation comparison will be made on "All" individual components. If there is a concern or discrepancy exists, a bench level correlation will be performed to ensure new site meets data sheet requirements.
- Running samples from 2 or more lots at the existing site and at new site location. The results from each site will be compared.
- Running (the same) sample non-continuity failures (different failing tests) and testing them at the existing site and at the new site. All units are expected to fail at the new site location.
- Performing GR&R (Gauge Repeatability & Reproducibility)